

Yuyao Tongtai Electric Co., Ltd. TEST REPORT

SCOPE OF WORK: EMC directive (2014/30/EU) – EMC report

Model: FT2001, details refer to Page 7

REPORT NUMBER 171101667SHA-001/Amendment1

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Manufacturer	 Yuyao Tongtai Electric Co., Ltd. No.116, Zhenxing East Road, Mingwei Industry Zone, Lizhou Street, Yuyao City, Ningbo, China
Manufacturing site	 Yuyao Tongtai Electric Co., Ltd. No.116, Zhenxing East Road, Mingwei Industry Zone, Lizhou Street, Yuyao City, Ningbo, China

Summary

The equipment complies with the requirements according to the following standard(s) or Specification: ***EN 55014-1:2017**: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 1: Emission

EN 55014-2:2015: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 2: Immunity – Product family standard

EN 61000-3-2:2014: Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current ≤ 16A per phase)

EN 61000-3-3:2013: Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current \leq 16A per phase and not subject to conditional connection

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Revision History

Report No.	Version	Description	Issued Date
171101667SHA-V1	Rev. 01	Initial issue of report	February 08, 2018



Measurement result summary

TEST ITEM	TEST RESULT	NOTE
Mains terminal continuous disturbance voltage	Pass	
Mains terminal discontinuous disturbance voltage/click	Pass	
Continuous disturbance power	Pass	
Radiated Emission ⁽¹⁾	Pass	
Harmonics	Pass	
Voltage fluctuation-Flicker	Pass	
Electrostatic Discharge (ESD)	Pass	
RF electromagnetic field susceptibility	NA	
Electric Fast Transient /Burst (EFT/B)	Pass	
Surge	Pass	
Injected Current	Pass	
Voltage dips and interruption	Pass	

Notes:

- 1. The item(s) in "bold & italic" means the additional tests has been performed, and test result will be listed in the ANNEX of this amendment report.
- 2. NA=Not Applicable.
- 3. Determination of the test conclusion is based on IEC Guide 115 in consideration of measurement uncertainty.
- ⁽¹⁾ As for in the disturbance power test all emission readings from the EUT are lower than the applicable limits (Table 7) reduced by the margin (Table 8) and the maximum clock frequency is less than 30MHz, the EUT is deemed to comply with the Radiated Emission requirement without test.

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1. GENERAL INFORMATION

1.1 Description of Equipment Under Test (EUT)

- Product name : Toaster for household use
- Type/Model
 :
 FT2001, FT2001-T, FT2001-BW, FT2001-T-BW, FT2001A, FT2001A-T, FT2001A-BW, FT2001A-T-BW, FT2001B, FT2001B-T, FT2001B-BW, FT2001B-T-BW, FT2002, FT2002-BW, FT2002-T, FT2002-T-BW, FT2003, FT2003-T, FT2003-FL, FT2003-FL, FT2003-BW, FT2003-T-BW, FT2003-T-FL, FT2003-FL-BW, FT2003-FL-BW, FT2003A, FT2003A-T, FT2003A-BW, FT2003A-T, FT2003A-T-BW, FT2004-BW, FT2004-FL, FT2004-FL-BW, FT2004-T, FT2004-T, FT2004-T, FT2004-T-FL, FT2004-T-FL, FT4003-FL, FT4003-FL, FT4003-FL, FT4003-T-FL, FT4003-T-FL, FT4003-T-FL, FT4003-T-FL, FT4003-T-FL, FT4003-T-FL
- The appliances covered in this test report are considered as toasters Description of EUT : intended to household and indoor use. All models incorporate bare heating element, integrated circuit, all-pole disconnection switch. FT2001 series, FT2001B series are same except for minor different shape of top metal. FT2001 series, FT2001A series are same except for different control PCB, so do FT2003 series and FT2003A series. FT2001 series, FT2003 series are same except for different appearance, so do FT2001A series and FT2003A series. FT4003 series has two more slots than FT2003 series. Suffix "-T" in the model name indicates the model has a PCB with metal shrapnel switch. Suffix "-BW" in the model name indicates the model employed a device for heating rolls. Suffix "-FL" in the model name for FT2003 series, FT2004 series, FT4003 series indicates the model has a PCB with 3 LED lights, and without suffix "-FL" in the model name for FT2003 series, FT2004 series, FT4003 series indicates the model has a PCB with 2 LED lights.
 - Rating : 220-240V~, 50/60Hz, Class I FT2001, FT2001-T, FT2001-BW, FT2001-T-BW, FT2001A, FT2001A-T, FT2001A-BW, FT2001A-T-BW, FT2001B, FT2001B-T, FT2001B-BW, FT2001B-T-BW, FT2003, FT2003-T, FT2003-FL, FT2003-BW, FT2003-T-BW, FT2003-T-FL, FT2003-FL-BW, FT2003-T-FL-BW, FT2003A, FT2003A-T, FT2003A-BW, FT2003A-T-BW: 650-750W; FT2002, FT2002-BW, FT2002-T, FT2002-T-BW : 700-850W; FT4003, FT4003-BW, FT4003-FL, FT4003-FL-BW, FT4003-T, FT4003-T-BW, FT4003-T-FL, FT4003-T-FL-BW: 1300-1500W FT2004, FT2004-BW, FT2004-FL, FT2004-FL-BW, FT2004-T, FT2004-T-BW, FT2004-T-FL, FT2004-T-FL-BW: 750-900W

Brand name : NIL

Mains lead : 0.8m, (un)shielded, (non)detachable

Data cable : /

2018

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EUT type	:	⊠ Table-top ☐ Floor standing
EUT is toy, defined as		 Category A Category B Category C Category D Category E
Sample received date	:	September 12, 2018
Sample Identification No.	:	/
Date of test	:	September 12, 2018- September 25,

Amendment 1:

The original test report ref. No. 171101667SHA-001 dated February 08, 2018 was modified on October 16, 2018 to include the following additions and/or changes:

- (1) "*" means the standard has been updated by the new standards listed in this report, and there is no difference on this kind of products between the new standard and the old one. No additional testing is required accordingly.
- (2) Added 37 models: FT2001-T, FT2001-BW, FT2001-T-BW, FT2001A-T, FT2001A-BW, FT2001A-T-BW, FT2001B-T, FT2001B-BW, FT2001B-T-BW, FT2002-BW, FT2002-T, FT2002-T-BW, FT2003-T, FT2003-FL, FT2003-BW, FT2003-T-BW, FT2003-T-FL, FT2003-FL-BW, FT2003-T-FL-BW, FT2003A-T, FT2003A-BW, FT2003A-T-BW, FT2004, FT2004-BW, FT2004-FL, FT2004-FL-BW, FT2004-T, FT2004-T-BW, FT2004-T-FL, FT2004-T-FL-BW, FT4003-BW, FT4003-FL, FT4003-FL-BW, FT4003-T, FT4003-T-FL, FT4003-T-FL, FT2004-T-FL, FT2004-T-FL-BW. All models have the similar construction and critical component, some characteristic as following: Suffix "-T" in the model name indicates the model has a PCB with metal shrapnel switch. Suffix "-BW" in the model name indicates the model employed a device for heating rolls. Suffix "-FL" in the model name for FT2003 series, FT4003 series indicates the model has a PCB with 3 LED lights, and without suffix "-FL" in the model name for FT2003 series, FT2003 series, FT2003 series, FT4003 series indicates the model has a PCB with 2 LED lights.

Therefore, we test FT2004 and the worst test data is listed in the report as representative. This amendment test report should be read in conjunction with the based test report.

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1.2 Description of Test Facility

Name	:	Intertek Testing Services Shanghai
Address	:	Building 86, No. 1198 Qinzhou Road(North), Shanghai 200233, P.R. China
Telephone	:	86 21 61278200
Telefax	:	86 21 54262353
The test facility is recognized, certified, or accredited by these organizations	:	CNAS Accreditation Lab Registration No. CNAS L0139 FCC Accredited Lab Designation Number: CN1175 IC Registration Lab
		Registration code No.: 2042B-1 VCCI Registration Lab Registration No.: R-4243, G-845, C-4723, T-2252
		NVLAP Accreditation Lab NVLAP LAB CODE: 200849-0
		A2LA Accreditation Lab Certificate Number: 3309.02

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2. TEST SPECIFICATIONS

2.1 Normative Standards

IEC 61000-4-2:2008: Electromagnetic Compatibility (EMC) – Part 4-2: testing and measurement techniques – electrostatic discharge immunity test

IEC 61000-4-3:2006+A1:2007+A1:2010: Electromagnetic Compatibility (EMC) – Part 4-3: testing and measurement techniques – radiated, radio frequency, electromagnetic field immunity test

IEC 61000-4-4:2012: Electromagnetic Compatibility (EMC) – Part 4-4: testing and measurement techniques – electric fast transient/burst immunity test

IEC 61000-4-5:2014: Electromagnetic Compatibility (EMC) – Part 4-5: testing and measurement techniques – section 5: surge immunity test

IEC 61000-4-6:2013: Electromagnetic Compatibility (EMC) – Part 4-6: testing and measurement techniques – section 6: immunity to conducted disturbance, induced by radio frequency field

IEC 61000-4-11:2004: Electromagnetic Compatibility (EMC) – Part 4-11: testing and measurement techniques –voltage dips, short interruption and voltage variations immunity test

IEC 61000-4-22:2010: Electromagnetic compatibility (EMC) – Part 4-22: Testing and measurement techniques – Radiated emissions and immunity measurements in fully anechoic rooms (FARs)

Note: there are no magnetic sensitive components included in this EUT and magnetic field immunity test according to EN 61000-4-8 is therefore not required.



2.2 Mode of operation during the test

Within this test report, EUT was tested under all available operation modes and tested under its rating voltage and frequency. Other voltage and frequency is specified if used.

2.3 Test Peripherals used

Item No	Description	Band and Model	S/No
1	-	-	-

2.4 Record of climatic conditions

Test Item	Temperature (°C)	Relative Humidity (%)	Pressure (Kpa)
Mains terminal continuous disturbance voltage	24	42	NA
Mains terminal discontinuous disturbance voltage/click	24	42	NA
Continuous disturbance power	24	42	NA
Radiated Emission	NA	NA	NA
Harmonics	24	42	NA
Voltage fluctuation-Flicker	24	42	NA
Electrostatic Discharge (ESD)	23	41	101
RF electromagnetic field susceptibility	NA	NA	NA
Electric Fast Transient /Burst (EFT/B)	23	41	NA
Surge	23	41	NA
Injected Current	23	41	NA
Voltage dips and interruption	23	41	NA

Notes: NA =Not Applicable

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2.5 Instrument list

	Conducted Emission/Disturbance Power/Tri-loop Test/CDN method					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
K	Test Receiver	R&S	ESCS 30	EC 2107	2019-09-12	
K	A.M.N.	R&S	ESH2-Z5	EC 3119	2019-07-17	
	A.M.N.	R&S	ENV 216	EC 3393	2019-07-04	
	A.M.N.	R&S	ENV4200	EC 3558	2019-06-10	
>	Absorbing clamp	R&S	MDS 21	EC 2108	2019-06-19	
	CDN	Frankonia	CDN M2M316	EC 5969	2019-03-15	
	CDN	Schaffner	CDN M316	EC 2113-1	2019-07-16	
	Attenuator	Weinschel	68-6-44	EC 3043-9	2019-02-05	
	Tri-loop	Schwarzbeck	HXYZ 9170	EC 3384	2018-10-11	
	Voltage Probe	Schwarzbeck	ТК9420	EC 4888	2019-09-11	
	Current probe	R&S	EZ-17	EC 3221	2019-03-14	
	I.S.N.	FCC	FCC-TLISN-T2-02	EC 3754	2019-02-05	
	I.S.N.	FCC	FCC-TLISN-T4-02	EC 3755	2019-02-05	
	I.S.N.	FCC	FCC-TLISN-T8-02	EC 3756	2019-02-05	
Radiate	d Emission					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
	Test Receiver	R&S	ESIB 26	EC 3045	2019-09-12	
	Bilog Antenna	TESEQ	CBL 6112D	EC 4206	2019-06-10	
	Pre-amplifier	R&S	Pre-amp 18	EC5262	2019-06-10	
	Horn antenna	R&S	HF 906	EC 3049	2018-11-17	
	Horn antenna	ETS	3117	EC 4792-1	2019-01-09	
	Horn antenna	ΤΟΥΟ	HAP18-26W	EC 4792-3	2019-07-09	
	Pre-amplifier	R&S	Pre-amp 18	EC5262	2019-06-10	
	Active loop antenna	Schwarzbeck	FMZB1519	EC 5345	2019-03-07	
Harmon	ics / Flicker / Low-fred	uency immunity to	est			
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
	Harmonic-flicker	CI	5001ix-PACS-1	EC 2110	2018-11-08	
	Three phase	EM TEST	PFS 503N	EC 5383-1	2019-09-10	
N	Harmonic-flicker system	EM TEST	DPA 503N	EC 5383	2019-01-31	
ESD						
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
>	ESD generator	TESEQ	NSG 437	EC 4792-4	2019-03-22	

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EFT/Sur	ge Voltage Dips				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
	Conduct immunity system	EM TEST	UCS 500M6B	EC 2958	2019-04-07
Y	Automatic transformer	EM TEST	MV2616	EC 2957	2019-04-07
	Capacity clamp	EM TEST	HFK	EC 2959	2019-02-13
	Surge generator	EM TEST	TSS 500M2F	EC 2960	2019-08-07
	Surge generator	EM TEST	TSS 500M4	EC 2961	2019-01-05
	Surge Coupling network	EM TEST	CNV 504M	EC 2958-2	2019-02-05
	Surge Coupling network	EM TEST	CNV 504S1	EC 2958-1	2019-02-05
	DIPs generator	SANKI	SKS-1130GT	EC 5033	2019-01-04
	Ring wave generator	SANKI	SKS-1206GB	EC 5033-1	2019-01-04
	EFT generator	SANKI	SKS-0404IB	EC 5033-3	2019-03-08
	Surge generator	SANKI	SKS-0506GB-30	EC 5033-2	2019-03-08
Conduc	ted Immunity				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
	Signal generator	R&S	SML 01	EC 2338	2019-09-10
	Power amplifier	AR	75A250	EC 3043-1	2019-07-15
>	Attenuator	EM TEST	ATT6/75	EC 3043-3	2019-02-05
	CDN	Frankonia	CDN M2M316	EC 5969	2019-03-15
	CDN	Schaffner	CDN M316	EC 2113-1	2019-07-29
	CDN	EM TEST	CDN T2	EC 4970	2019-09-06
	CDN	EM TEST	CDN T4	EC 3043-4	2019-02-05
	CDN	EM TEST	CDN M1/16A	EC 4792-6	2018-10-08
	CDN	EM TEST	CDN M1/16A	EC 4792-7	2019-09-06
	CDN	EM TEST	CDN M1/32A	EC4792-10	2019-02-05
	CDN	EM TEST	CDNM3N/16A	EC 4792-12	2019-02-05
	CDN	EM TEST	CDNM3N/32A	EC 4792-13	2019-02-05
	CDN	EM TEST	CDN T8-RJ45	EC 4792-15	2019-09-06
	EM clamp	EM TEST	EM 101	EC 3043-6	2018-12-07
	DDC	AR	DC 2600	EC 3043-5	2019-02-05
Radiate	d Immunity				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
	Signal generator	R&S	SMR 20	EC 3044-1	2019-02-23

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	Power amplifier	AR	250W1000B	EC 5818-2	2019-04-19
	Power amplifier	BONN	BLMA1060-100	EC 5818-4	2019-04-18
	Log-period antenna	AR	AT 1080	EC 3044-7	2019-01-03
	Horn antenna	AR	AT 4002	EC 3044-8	2018-11-30
	Horn antenna	Schwarzbeck	STLP 9149	EC5881	2019-06-19
	Field meter	AR	FL7006	EC 5818-1	2019-05-10
	Power sensor	Keysight	N1914A	EC 5818-3	2019-04-18
RF test					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
	PXA Signal Analyzer	Keysight	N9030A	EC 5338	2019-03-05
	Power sensor	Agilent	U2021XA	EC 5338-1	2019-03-05
	Vector Signal Generator	Agilent	N5182B	EC 5175	2019-03-05
	Spectrum analyzer	R&S	CMW500	EC5944	2018-12-07
	MXG Analog Signal Generator	Agilent	N5181A	EC 5338-2	2019-03-05
	Mobile Test System	Litepoint	lqxel	EC 5176	2019-01-05
	Test Receiver	R&S	ESCI 7	EC 4501	2019-09-12
Test Sit	e				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
Used	Equipment Shielded room	Manufacturer Zhongyu	Type -	Internal no. EC 2838	Due date 2019-01-07
Used V	Equipment Shielded room Shielded room	Manufacturer Zhongyu Zhongyu	Туре - -	Internal no. EC 2838 EC 2839	Due date 2019-01-07 2019-01-14
Used V V	Equipment Shielded room Shielded room Semi-anechoic chamber	Manufacturer Zhongyu Zhongyu Albatross project	Туре - - -	Internal no. EC 2838 EC 2839 EC 3048	Due date 2019-01-07 2019-01-14 2019-05-24
Used V	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber	Manufacturer Zhongyu Zhongyu Albatross project Albatross project	Туре - - - -	Internal no. EC 2838 EC 2839 EC 3048 EC 3047	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24
Used V V Addition	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber	Manufacturer Zhongyu Zhongyu Albatross project Albatross project	Туре - - - -	Internal no. EC 2838 EC 2839 EC 3048 EC 3047	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24
Used	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber nal instrument Equipment	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer	Туре - - - - - Туре	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 Internal no.	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date
Used	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber nal instrument Equipment Spectrum analyzer	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent	Type - - - - - - - - - - - - - - - - E7402A	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12
Used	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber nal instrument Equipment Spectrum analyzer Therom- Hygrograph	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A	Type - - - - - - - - - - - - - - -	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254 EC 2323	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12 2019-06-07
Used	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber nal instrument Equipment Spectrum analyzer Therom- Hygrograph Therom- Hygrograph	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A ZJ1-2A	Type - - - - - - - - - - - S.M.I.F. S.M.I.F.	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254 EC 2323 EC 3324	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12 2019-06-07 2019-04-15
Used	Equipment Shielded room Shielded room Semi-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Fully-anechoic chamber Therom- Hygrograph Therom- Hygrograph	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A ZJ1-2A	Type - - - - - - - - - - S.M.I.F. S.M.I.F. S.M.I.F.	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 EC 2254 EC 2323 EC 2323 EC 3324	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12 2019-06-07 2019-04-15 2019-03-28
Used	EquipmentShielded roomShielded roomShielded roomSemi-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberSpectrum analyzerTherom-HygrographTherom-HygrographTherom-HygrographTherom-Hygrograph	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A ZJ1-2A ZJ1-2A	Type - - - - - - S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F.	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254 EC 2323 EC 3324 EC 3325 EC 3326	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12 2019-09-12 2019-06-07 2019-04-15 2019-03-28 2019-03-28
Used	EquipmentShielded roomShielded roomShielded roomSemi-anechoicchamberFully-anechoicchamberFully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicchamberfully-anechoicfully-anech	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A ZJ1-2A ZJ1-2A ZJ1-2A	Type - - - - - - E7402A S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F.	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254 EC 2323 EC 3324 EC 3325 EC 3326 EC 3320	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 2019-05-24 2019-05-24 2019-05-24 2019-05-24 2019-05-24 2019-05-24 2019-03-28 2019-06-27
Used V Addition Used V V V V V V V V V V V V V	EquipmentShielded roomShielded roomShielded roomSemi-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberFully-anechoicchamberSpectrum analyzerTherom-HygrographTherom-HygrographTherom-HygrographTherom-HygrographPressure meterNuous Disturbance Volt	Manufacturer Zhongyu Zhongyu Albatross project Albatross project Manufacturer Agilent ZJ1-2A ZJ1-2A ZJ1-2A ZJ1-2A YM3	Type - - - - - - F7402A S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F. S.M.I.F.	Internal no. EC 2838 EC 2839 EC 3048 EC 3047 EC 3047 Internal no. EC 2254 EC 2323 EC 3324 EC 3325 EC 3326 EC 3320	Due date 2019-01-07 2019-01-14 2019-05-24 2019-05-24 Due date 2019-09-12 2019-06-07 2019-04-15 2019-03-28 2019-06-27

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2	Click meter	AFJ	DDA55	EC 5320	2019-03-08
	A.M.N.	AFJ	LS16C	EC 5320-1	2018-12-07
>	Shielded room	Zhongyu	-	EC 2838	2019-01-07



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2.6 Measurement Uncertainty

Measurement	Frequency	Expanded Uncertainty (k=2) (±)
Conducted emission at mains north	9kHz ~ 150kHz	3.52 dB
Conducted emission at mains ports	150kHz ~ 30MHz	3.19 dB
Continuous disturbance voltage at telecom ports	150kHz ~ 30MHz	3.64 dB
Continuous disturbance current at telecom ports	150kHz ~ 30MHz	2.62 dB
Mains terminal discontinuous disturbance voltage/click	-	3.76 dB
Continuous disturbance power	30MHz ~ 300MHz	4.35 dB
Radiated Emissions up to 1 GHz	30MHz ~ 1GHz	4.90 dB
Padiated Emissions above 1 GHz	1GHz ~ 6GHz	5.02 dB
	6GHz ~ 18GHz	5.28 dB
Harmonic current emission	-	3.90%
Voltage fluctuations and flicker	-	10.34%
ESD	-	6.65%
Radiated susceptibility	-	2.38%
EFT test at main terminal	-	11.57%
EFT test at signal/telecom terminal	-	11.62%
Surge test at main terminal	-	11.57%
Injected current test at main terminal	-	1.88 dB
Injected current test at unshielded signal terminal	-	3.41 dB
Voltage dips and interruption	-	6.05%



Emission Test

3. Mains/Load/Control Terminal Continuous Disturbance Voltage

Test result: PASS

3.1 Terminal Voltage Limits for the frequency range 9kHz to 30MHz

3.1.1 General limits

Frequency range	Mains	s ports	Associated ports			
	Disturbance voltage		Disturbance voltage		Disturbance current	
(11112)	Limits dB(µV)		Limits dB(µV)		Limits dB(μV)	
	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
0.15 ~ 0.5	66 ~ 56 *	59 ~ 46 *	80	70	40 ~ 30 *	30 ~ 20 *
0.5 ~ 5.0	56	46	74	64	20	20
5.0 ~ 30	60	50	74	64	30	20
Notes:						
1. * means the limit decreasing linearly with the logarithm of the frequency in the					in the	

range 0.15MHz to 0.5MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.

3.1.2 Limits for mains port of tools

	P ≤ 700 W		700 W < P ≤ 1 000 W		P > 1 000 W	
Frequency range	Limits dB(µV)		Limits dB(µV)		Limits dB(µV)	
(MHz)	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peal	< Average
0.15-0.35	66-59*	59-49*	70-63*	63-53*	76-69*	69 ~ 59 *
0.35-5	59	49	63	53	69	59
5-30	64	54	68	58	74	64

Notes:

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.35MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.



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3.2 Block Diagram of Test Setup

At mains terminal



For table top equipment, wooden support is 0.8m height table

For floor standing equipment, wooden support is 0.1m height rack.







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3.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9kHz.

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3.4 Test Protocol

For Mains ports: Pass

L-Line

EN 55014 Voltage HA on Mains



N-Line

EN 55014 Voltage HA on Mains



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		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
0.160000	*	65.46	*	*	58.30	*
0.240000	*	62.10	*	*	53.93	*
0.550000	*	56.00	*	*	46.00	*
1.000000	*	56.00	*	*	46.00	*
1.400000	*	56.00	*	*	46.00	*
2.000000	*	56.00	*	*	46.00	*
3.500000	*	56.00	*	*	46.00	*
6.000000	*	60.00	*	*	50.00	*
10.000000	*	60.00	*	*	50.00	*
22.000000	*	60.00	*	*	50.00	*
30.000000	*	60.00	*	*	50.00	*
Note: * means th	e emission le	evel 10dB lov	wer than the	e relevant lim	iit.	

For Associated ports: NA

		Quasi-peak		Average			
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	
Note: * means th	Note: * means the emission level 20dB below the relevant limit.						

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Mains terminal discontinuous disturbance voltage/click 4.

Test result: PASS

4.1 **Block Diagram of Test Setup**



4.2 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

0.15MHz, 0.5MHz, 1.4MHz and 30MHz were spot checked, and upper quartile methods used during measurement.

The final judgment of test result was according to figure 6 of EN 55014-1.

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4.3 Test Protocol

Frequency		. -		
(MHz)	0.15	0.5	1.4	30.0
Permitted limit				
for continuous interference	66.0	56.0	56.0	60.0
(dBμV)				
	38	40	0	0
Counted click number				
	30	30	30	30
Observed time (min)				
	<10	<10	-	-
Click duration (ms)				
Click rate N	<5	<5	<5	<5
	-	-	-	-
Factor				
	-	-	-	-
Permitted limits for clicks (dBµv)				
	-	-	-	-
Counted clicks exceeding the				
limits				
	Pass	Pass	Pass	Pass
Test result				

Any other descriptions: The click rate is less than 5, the caused clicks have a duration is less than 10ms, so it is deemed to comply with the limits without further testing.

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5. Continuous disturbance power

Test result: PASS

5.1 Continuous disturbance power limit

	General		P ≤ 700 W		700 W < P ≤ 1 000 W		P > 1 000 W	
Frequency range	Limits dB(pW)		Limits dB(pW)		Limits dB(pW)		Limits dB(pW)	
(MHz)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
30-300	45-55*	35-45*	45-55*	35-45*	49-59*	39-49*	55-65*	45 55*

Notes:

* means the limit decreasing linearly with the logarithm of the frequency in the range 30MHz to 300MHz.
 If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and

the measurements using the average detector need not be carried out.

5.2 Block diagram of test set up



5.3 Test Procedure

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.3 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

Frequency range 30MHz – 300MHz was checked and EMI receiver measurement bandwidth was set to 120kHz.

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5.4 Test Protocol

For Mains ports: Pass



EN 55014 Power HAPT

		Quasi-peak		Average		
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
30.000000	25.64	45.00	19.36	19.20	35.00	15.80
31.920000	31.46	45.07	13.61	24.85	35.07	10.22
37.120000	30.62	45.26	14.64	24.48	35.26	10.78
45.000000	23.62	45.56	21.94	17.26	35.56	18.30
50.000000	24.85	45.74	20.89	18.50	35.74	17.24
65.000000	22.31	46.30	23.99	15.93	36.30	20.37
90.000000	20.88	47.22	26.34	14.53	37.22	22.69
150.000000	20.67	49.44	28.77	14.29	39.44	25.15
180.000000	20.47	50.56	30.09	14.12	40.56	26.44
220.000000	20.50	52.04	31.54	14.15	42.04	27.89
300.000000	20.88	55.00	34.12	14.54	45.00	30.46



For Associated ports: NA

		Quasi-peak		Average				
Frequency (MHz)	Corrected Reading (dBpW)	Limit (dBpW)	Margin (dB)	Corrected Reading (dBpW)	Limit (dBpW)	Margin (dB)		
Note: * means th	Note: * means the emission level 20dB below the relevant limit.							

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6. Radiated emission

Test result: PASS

As for in the disturbance power test all emission readings from the EUT are lower than the applicable limits (Table 7) reduced by the margin (Table 8) and the maximum clock frequency is less than 30MHz, the EUT is deemed to comply with the Radiated Emission requirement without test.

6.1 Limit

Radiated emission limit from frequency range 30MHz – 1000MHz

Frequency (MHz)	Permitted limit in dBµV/m	Permitted limit in dBµV/m						
	(Quasi-peak)	(Quasi-peak)						
	of Measurement Distance	of Measurement Distance						
	3m	10m						
30 ~ 230	40	30						
230 ~ 300	47	37						
Notes:								
1. For the measurement distance other than 3m and 10m, the limit is varied according to								
20dB/10 decades.								

2. The gray rows are selected items.

6.2 Block diagram and test set up



The measurement was applied in a semi-anechoic chamber.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

Measurement was performed according to clause 10 of CISPR 32.

Setting of EUT is according to clause 5.3.4.3 of EN 55014-1.

The bandwidth setting on test receiver was 120kHz.

The frequency range from 30MHz to 300MHz was checked.



6.3 Test Protocol

Horizontal

Vertical

Polarization	Frequency (MHz)	Corrected Reading (dBuV/m)	Corrected Factor (dB/m)	Limits (dBuV/m)	Margin (dBuV/m)
Horizontal					
Vertical					



7. Harmonics

Test result: PASS

7.1 Block Diagram of Test Setup



7.2 Test Setup and Test Procedure

Harmonics of the fundamental current were measured up to 40 order harmonics using a digital power meter with an analogue output and frequency analyser which was integrated in the harmonic & flicker test system. The measurements were carried out under steady conditions.



Measuring instrumentation according to IEC 61000-4-7:2002+A1:2008

This product is not defined as lighting equipment, and has rated power less than 75W, therefore, no limit apply according to EN 61000-3-2

The EUT is kitchen machines as listed in the scope of IEC 60335-2-14, therefore, is deemed to conform to the harmonic current limits of this standard without further testing.

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7.3 Tes	st Protocol					
Power	and THD rea	sults ·	- DS: 1			
True power	· P: 843	3.2W	A	pparent power S:	84	3.2VA
Reactiv pov	ver Q: 5.0	15var	P	ower factor:	1.0	000
тнр (ц)·	0.0	01	т	HD (I).	0.0	005
Croct Costo	~ (II). 1.4	1.4		rest Fastar (I).	1	419
	e harmonic		nt result		1.4	+18
Averag					,	
Hn	Ieff [A]		% of Limit	Limit (A	J	Result
1	3.03U					DACC
2	11.830E-3 9.027E 2					PASS
5	0.937E-3 E 032E 3					PASS
4 5	J.955E-5					PASS
5	4.0322-5					PASS
7	1.0322-3					PASS
, ,	1.3322-3					PASS
0	1.303L-3					
10	1.294L-3 881 520E-6					
10	1 201E-2					
12	1.301L-3 807 222F-6					PASS
12	962 899F-6					ΡΔςς
1/	1 032F-3					ΡΔςς
15	1.052E 3					ΡΔςς
16	741 472F-6					PASS
17	1 507F-3					PASS
18	866 643E-6					PASS
19	905 340F-6					PASS
20	719.536F-6					PASS
21	1.173F-3					PASS
22	744.161F-6					PASS
23	1.464E-3					PASS
24	674.021E-6					PASS
25	699.765E-6					PASS
26	750.546E-6					PASS
27	1.353E-3					PASS
28	874.590E-6					PASS
29	1.149E-3					PASS
30	715.652E-6					PASS
31	781.614E-6					PASS
32	864.549E-6					PASS
33	1.201E-3					PASS
34	673.460E-6					PASS
35	961.248E-6					PASS
36	681.029E-6					PASS
37	850.301E-6					PASS
38	673.947E-6					PASS
39	1.390E-3					PASS
40	682.533E-6					PASS

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waxim	um narmonic d	surrent results		
Hn	leff [A]	% of Limit	Limit [A]	Result
1	3.650			
2	12.369E-3			PASS
3	9.418E-3			PASS
4	6.226E-3			PASS
5	4.423E-3			PASS
6	1.214E-3			PASS
7	1.746E-3			PASS
8	1.740E-3			PASS
9	1.636E-3			PASS
10	1.155E-3			PASS
11	1.489E-3			PASS
12	1.111E-3			PASS
13	1.356E-3			PASS
14	1.157E-3			PASS
15	1.364E-3			PASS
16	866.231E-6			PASS
17	1.734E-3			PASS
18	1.063E-3			PASS
19	1.079E-3			PASS
20	875.169E-6			PASS
21	1.509E-3			PASS
22	890.634E-6			PASS
23	1.699E-3			PASS
24	831.886E-6			PASS
25	842.089E-6			PASS
26	1.047E-3			PASS
27	1.743E-3			PASS
28	1.083E-3			PASS
29	1.399E-3			PASS
30	870.170E-6			PASS
31	917.636E-6			PASS
32	1.001E-3			PASS
33	1.413E-3			PASS
34	900.713E-6			PASS
35	1.123E-3			PASS
36	847.658E-6			PASS
37	1.041E-3			PASS
38	823.243E-6			PASS
39	1.635E-3			PASS
40	851.364E-6			PASS

Harmonic currents less than 0.6% of the input current measured under the test conditions, or less than 5 mA, whichever is greater, are disregarded.

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8. Voltage Fluctuations-Flicker

Test result: PASS

8.1 Block Diagram of Test Setup



8.2 Test Setup and Test Procedure

8.2.1 Definition

- Flicker: impression of unsteadiness of visual sensation induced by a light stimulus whose luminance or spectral distribution fluctuates with time.
- Pst: Short-term flicker severity.
- Plt: long-term flicker severity.
- dc: maximum steady state voltage change during an observation period.
- dmax: maximum absolute voltage change during an observation period.
- d(t): time function of the relative r.m.s. voltage change evaluated as a single value for each successive half period between zero-crossings of the source voltage, except during time interval in which the voltage is a steady-state condition for at least 1s.

8.2.2 Test condition

The EUT was set to produce the most unfavorable sequence of voltage changes.

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8.3 Test Protocol

The tested object operated under the operating condition specified in EN 61000-3-3 The following limits apply

- the value of Pst shall not be greater than 1,0.
- the value of Plt shall not be greater than 0,65.
- Tmax, the accumulated time value of d(t) with a deviation exceeding 3,3 % during a single voltage change at the EUT terminals, shall not exceed 500 ms.
- the maximum relative steady-state voltage change, dc, shall not exceed 3,3 %.
- the maximum relative voltage change dmax, shall not exceed:

4% without additional conditions.

6 % for equipment which is:

- switched manually, or
- switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.
- \boxtimes 7 % for equipment which is:

 – attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or

- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

for manual switch, dmax is measured in accordance with Annex B of standard, average dmax is calculated from 24 times measurement.

According to EN 61000-3-3 clause 6.1 & A.2, the EUT is either unlikely to produce significant voltage fluctuations/flicker or no limit and test were required by technical analysis and sample evaluation on the product.

The rate power of the EUT is no greater than 75W, which is unlikely to produce significant voltage fluctuations or flicker by technical analysis and evaluation. So it is deemed to fulfil the requirements without testing.

	EUT values	Limit	Result
Pst	0.096	1.00	PASS
dc [%]	0.681	3.30	PASS
dmax [%]	0.701	7.00	PASS
dt [s]	0.000	0.50	PASS



Immunity Test

Performance criteria

The performance criteria are based on the general criteria of the standard and derived from the product specification

Criterion A: Normal Performance within limits specified by the manufacturer, request or purchaser.

Criterion B: Continue to operate as intended after the test. No degradation of performance or loss of function. During the test degradation of performance is allowed, however no change of actual operating state or stored date.

Criterion C: Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls.

Categories of apparatus

Category I (fulfill the relevant immunity requirements without testing)

Category II (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips)

Category III (Shall fulfill the tests: ESD, EM fields*)

Category IV (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips, EM fields)

Note: *only applicable to the ride on toys operating with electronic devices.

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9. Electrostatic Discharge (ESD)

Test result: PASS

9.1 Severity Level and Performance Criterion

9.1.1 Test level

1a – Conta	ct discharge	1b – Air discharge		
Level	Test voltage kV	Level	Test voltage kV	
1	2	1	2	
2	4	2	4	
3	6	3	8	
4	8	4	15	
Х	Special	Х	Special	
NI - I				

Notes:

1."X" is an open level. The level has to be specified in the dedicated equipment specification. If higher voltages than those shown are specified, special test equipment may be needed.2. The gray rows were the selected test level.

9.1.2 Performance Criterion

Performance criterion: B

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9.2 Block Diagram of Test Setup

For table-top equipment



Note: VCP means <u>V</u>ertical <u>C</u>oupling <u>P</u>lane GRP means <u>G</u>round <u>R</u>eference <u>P</u>lane Wooden support is a 0.1m height rack



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9.3 Test Setup and Test Procedure

Measurement was performed in shielded room.

Measurement and setting of EUT was applied according to IEC 61000-4-2 Clasuse 7. The test method and equipment was specified by IEC 61000-4-2 with the modifications by EN 55014-2 clause 5.1.

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9.4 Test Protocol

Test point #	Test level [kV]	Air/ Contact	Polarity (+/-)	Pass/Fail/NA	Comment
А	2/4	Contact	+/-	Pass	All touchable screws of enclosure
В	2/4	Contact	+/-	Pass	Accessible metal parts of the EUT
С	2/4/8	Air	+/-	Pass	Air gap of the switch, button
D	2/4/8	Air	+/-	Pass	The air in-taking opening
E	2/4/8	Air	+/-	Pass	Slots around the EUT

Direct discharges were applied at the following selected points:

Indirect contact discharges were applied to the VCP and the HCP at the following selected points:

For table top equipment

Point	Description	Point	Pass/Fail/NA
HCP f	0,1m from the front of the EUT	Edge of centre, corner on HCP	Pass
HCP b	0,1m from the back of the EUT	Edge of centre, corner on HCP	Pass
HCP r	0,1m from the right side of the EUT	Edge of centre, corner on HCP	Pass
HCP I	0,1m from the left side of the EUT	Edge of centre, corner on HCP	Pass
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	Pass
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	Pass
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	Pass
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	Pass

For floor standing equipment

Point	Description	Point	Pass/Fail/NA
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	-
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	-
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	-
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	-

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

10. Electromagnetic field susceptibility

Test result: NA

10.1 Severity Level and Performance Criterion

10.1.1 Test level

Level	Test field strength V/m
1	1
2	3
3	10
Х	Special

Notes:

1. X is an open test level. This level may be given in the product specification.

2. The gray row is the selected test level.

10.1.2 Performance Criterion

Performance criterion: A



Total Quality. Assured.

10.2 Block diagram of test setup



10.3 Test Setup and Test Procedure

Measurement was performed in full-anechoic chamber. Measurement and setting of EUT was applied according to IEC 61000-4-3 clause 7. The test method and equipment was specified by IEC 61000-4-3 with additions and modifications by EN 55014-2 clause 5.5.

10.4 Test Protocol

Test no.:	Frequency (MHz)	Polarization	Test level V/m	Modulation	Exposed location	Pass/Fail/NA	Comment
1	80-1000	H & V	3	1kHz, 80%, SW, AM, 1% step size	All sides	-	-

Observation: Conclusion:

Total Quality. Assured.

Electric Fast Transient/Burst Immunity Test 11.

Test result: PASS

11.1 Severity Level and Performance Criterion

11.1.1 Test level

Open circuit output test voltage (±10%) and repetition rate of the impulses (±20%)					
	Input and output	a.c. power ports	Input and output d.c. power ports		
Level			Signal lines and c	ontrol lines ports	
	Voltage peak	Repetition rate	Voltage peak	Repetition rate	
	kV	kHz	kV	kHz	
1	0.5	5	0.25	5	
2	1	5	0.5	5	
3	2	5	1	5	
4	4	5	2	5	
Х	Special	Special	Special	Special	
Notes :					

Notes :

1. "X" is an open level. The level has to be specified in the dedicated equipment specification.

2. The gray rows were the selected test level.

11.1.2 Performance Criterion

Performance criterion **B**

Total Quality. Assured.

11.2 Block Diagram of Test Setup

11.2.1 Block Diagram for input a.c./d.c. power line

For table-top equipment





Total Quality. Assured.

11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

For table-top equipment



11.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-4 clause 7. The test method and equipment was specified by IEC 61000-4-4 with additions and modifications by EN 55014-2 clause 5.2.

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11.4 Test Protocol

Test No.	Level [kV]	Polarity +/-	Repetition rate kHz	Line for test	Pass/Fail/NA
1	1	+/-	5	a.c. power ports	Pass
2	0.5	+/-	5	d.c. power ports	NA
3	0.5	+/-	5	Signal lines and control lines	NA

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

12. Surge Immunity Test

Test result: PASS

12.1 Severity Level and Performance Criterion

12.1.1 Test level

Level	Open-circuit test voltage ±10%			
	K V			
1	0.5			
2	1.0			
3	2.0			
4	4.0			
X*	Special			
Notes: 1."X" is an open class. This level can be specified in the product Specification				

2. The gray rows are the selected level.

12.1.2 Performance Criterion

Performance criterion **B**

Total Quality. Assured.

12.2 Block Diagram of Test Setup



12.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-5 clause 7. The test method and equipment was specified by IEC 61000-4-5 with modifications by EN 55014-2 clause 5.6.

12.4 Test Protocol

Test	Level	Polarity	Angle	Line for test	Pass/Fail/NA
INO.	[κν]	+/-			
1	1	+	90 ⁰	a.c. Mains (line to earth)	NA
2	1	-	270 ⁰	a.c. Mains (line to earth)	NA
3	1	+	90 ⁰	a.c. Mains (line to line)	Pass
4	1	-	270 ⁰	a.c. Mains (line to line)	Pass
5	2	+	90 ⁰	a.c. Mains (line to earth)	Pass
6	2	-	270 ⁰	a.c. Mains (line to earth)	Pass

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

Immunity to Conducted Disturbances, Induced by Radio-frequency Fields 13.

Test result: PASS

Severity Level and Performance Criterion 13.1

13.1.1 Test level

Frequency range 150kHz – 80MHz					
Level	Voltage level (e.m.f.)				
	U ₀ [dB(uV)]	U ₀ (V)			
1	120	1			
2	130	3			
3	140	10			
Х	Special	Special			
Notes:					

2. The gray row is the selected test level.

13.1.2 Performance Criterion

Performance criterion: A

Block Diagram of Test Setup 13.2

13.2.1 Block Diagram for a.c./d.c input power line

Block Diagram for a.c./d.c input power line



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13.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

Unshielded line



Shielded line



13.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-6 clause 7. The test method and equipment was specified by IEC 61000-4-6 with additions and modifications by EN 55014-2 clause 5.3, 5.4.

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13.4 Test Protocol

EUT is not required for electromagnetic susceptibility

		0	1 /		
Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA
No.	(MHz)	V (r.m.s.)			
1	0.15~230	3	1kHz, 80%, SW,	a.c. power ports	Pass
			AM,		
			1% step size		
2	0.15~230	1	1kHz, 80%, SW,	d.c. power ports	-
			AM,		
			1% step size		
3	0.15~230	1	1kHz, 80%, SW,	signal lines and	-
			AM,	control lines	
			1% step size		

For EUT test Electromagnetic field susceptibility

Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA
No.	(MHz)	V (r.m.s.)			
1	0.15~80	3	1kHz, 80%, SW,	a.c. power ports	NA
			AM,		
			1% step size		
2	0.15~80	1	1kHz, 80%, SW,	d.c. power ports	-
			AM,		
			1% step size		
3	0.15~80	1	1kHz, 80%, SW,	signal lines and	-
			AM,	control lines	
			1% step size		

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

Voltage Dips, Short Interruptions and Voltage Variations Immunity Test 14.

Test result: PASS

14.1 **Severity Level and Performance Criterion**

14.1.1 Test level

Test level	Voltage dip and short	Duration (in period)	
	incerrapcions	(in pe	
% U _τ	% U _τ	50Hz	60Hz
0	100	0.5 cycle	0.5 cycle
40	60	10 cycles	12 cycles
70	30	25 cycles	30 cycles

Notes:

1."*" for 0.5 period, the test shall be made in positive and negative polarity, i.e. starting at 0° and 180° , respectively.

2. "**" means "x" is an open duration. This duration can be given in the product specification. Utilities in Europe have measured dips and short interruptions of duration between 1/2 a period and 3000 periods, but duration less than 50 periods are most common.

3. If the EUT is tested for voltage dips of 100%, it is generally unnecessary to test for other levels for the same durations. However, for some cases (safeguard systems or electro-mechanical devices) it is not true. The product specification or product committee shall give an indication of the applicability of this note.

4. The gray rows are selected test level.

14.1.2 Performance Criterion

Performance criterion: C

Total Quality. Assured.

14.2 Block diagram of test setup



14.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-11 clause 7. The test method and equipment was specified by IEC 61000-4-11 with additions and modifications by EN 55014-2 clause 5.7.

14.4 Test Protocol

Test no.	% U _τ	Voltage dip and short interruptions % UT	Duration (in periods)	Pass/Fail/NA
1	70	30%	25 cycles at 50Hz	Pass
			30 cycles at 60Hz	Pass
2	40	60%	10 cycles at 50Hz	Pass
			12 cycles at 60Hz	Pass
3	0	100% pos half cycle	0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	Pass
4	0	100% neg half cycle	0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	Pass

Observation: At test level of 70%, the EUT worked unsteadily. Once the interference is removed, it recovered its normal mode at once.

Conclusion: The EUT met the requirements of Performance Criterion B.

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Appendix I: Photograph of equipment under test

Photo 1. Description: Over view of FT2004



Photo 2. Description: Front view of FT2004





Photo 3.

Description: Side view of FT2004



Photo 4. Description: Side view of FT2004



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Photo 5.

Description: Top view of FT2004



Photo 6. Description: Bottom view of FT2004





Photo 7.

Description: Switch konb view of FT2004



Photo 8. Description: Internal view of FT2004





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Photo 9.

Description: Internal view of FT2004



Photo 10. Description: Internal view of FT2004





Photo 11.

Description: Heating element view of FT2004



Photo 12. Description: Power PCB view of FT2004





Photo 13.

Description: Power PCB view of FT2004



Photo 14. Description: Control PCB view of FT2004





Photo 15.

Description: Control PCB view of FT2004



Photo 16. Description: Earthing view of FT2004







Photo 17.

Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-T-FL"



Photo 18.

Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-FL"





Photo 17.

Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-FL"



Photo 18. Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-FL"





Photo 21.

Description: Power PCB view of FT2001 series, FT2001A series, FT2001B series, FT2002 series, FT2003 series, FT2003A series, FT2004 series, FT4003 series with suffix "-T"



Photo 22.

Description: Power PCB view of FT2001 series, FT2001A series, FT2001B series, FT2002 series, FT2003 series, FT2003A series, FT2004 series, FT4003 series with suffix "-T"





Photo 23. Description: Control PCB view of FT2001 series, FT2001B series with suffix "-T"



Photo 24. Description: Control PCB view of FT2001 series, FT2001B series with suffix "-T"





Photo 25.

Description: Control PCB view of FT2001A series with suffix "-T"



Photo 26. Description: Control PCB view of FT2001A series with suffix "-T"



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Photo 27.

Description: Control PCB view of FT2002 series with suffix "-T"



Photo 28. Description: Control PCB view of FT2002 series with suffix "-T"



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Photo 29.

Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-T"



Photo 30.

Description: Control PCB view of FT2003 series, FT2004 series, FT4003 series with suffix "-T"

Rq n



Photo 31.

Description: Over view of FT2001 series, FT2001A series, FT2001B series with suffix "-BW"



Photo 32. Description: Over view of FT2002 series with suffix "-BW"



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Photo 33.

Description: Over view of FT2003 series, FT2003A series with suffix "-BW"



Photo 34.

Description: Over view of FT4003 series with suffix "-BW"



END of the report